



S/N 09/943324

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Kie Y. Ahn et al. Examiner: Phuc Dang
Serial No.: 09/943324 Group Art Unit: 2818
Filed: August 30, 2001 Docket: 303.678US3
Title: STRUCTURE AND METHOD FOR DUAL GATE OXIDE THICKNESSES

COMMUNICATION CONCERNING CO-PENDING APPLICATION(S)

Mail Stop RCE
Commissioner for Patents
P.O.Box 1450
Alexandria, VA 22313-1450

Applicants would like to bring to the Examiner's attention the following related co-pending application(s) in the above-identified patent application:

<u>Serial No.</u>	<u>Filing Date</u>	<u>Attorney Docket</u>	<u>Title</u>
09/943398	August 30, 2001	303.678US2	STRUCTURE AND METHOD FOR DUAL GATE OXIDE THICKNESSES
09/943393	August 30, 2001	303.678US4	STRUCTURE AND METHOD FOR DUAL GATE OXIDE THICKNESSES

Respectfully submitted,

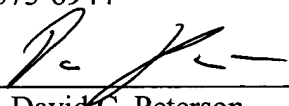
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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Mail Stop RCE, Commissioner of Patents, P.O.Box 1450, Alexandria, VA 22313-1450, on this 17th day of July, 2003.

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